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April 1st, 2010 Renesas Electronics Corporation

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R1LV0816ASD -5SI, 7SI

8Mb Advanced LPSRAM (512k word x 16bit / 1M word x 8bit)

REJ03C0397-0001 Preliminary Rev.0.01 2009.12.08

Description

The R1LV0816ASD is a family of low voltage 8-Mbit static RAMs organized as 524,288-words by 16-bit, fabricated by Renesas's high-performance 0.15um CMOS and TFT technologies. The R1LV0816ASD is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

The R1LV0816ASD is packaged in a 52pin thin small outline mount device [µTSOP/ 10.79mm x 10.49 mm with the pin-pitch of 0.40mm]. It gives the best solution for a compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

Features

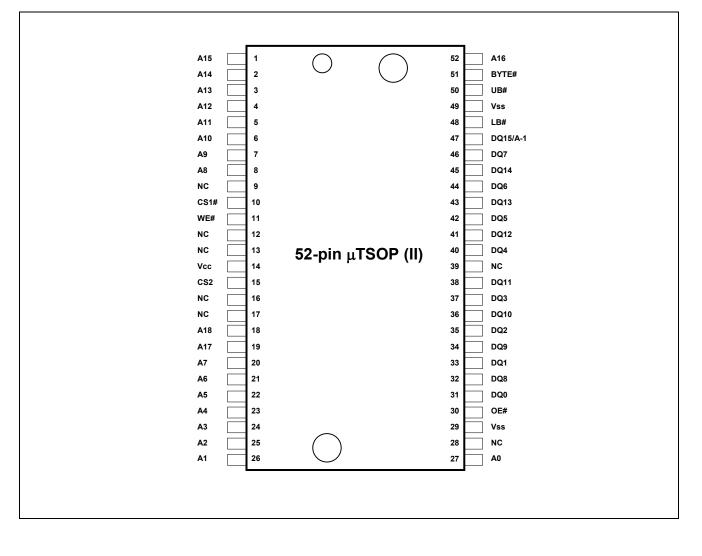
- Single 2.4-3.6V power supply
- Small stand-by current: 1.2µA (Vcc=3.0V, typ.)
- No clocks, No refresh
- All inputs and outputs are TTL compatible
- Easy memory expansion byCS2, CS1#, LB# and UB#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE# prevents data contention in the I/O bus
- Operation temperature: -40 ~ +85°C

Ordering information

Туре No.	Power supply	Access time	Temperature Range	Package		
R1LV0816ASD-5SI	2.7V to 3.6V 55 ns		250 mil 52 nin plaatie TSOD (II)			
R120010A3D-331	2.4V to 2.7V	.4V to 2.7V 70 ns -40 ~ +85°C		350 mil 52-pin plastic μ-TSOP (II)		
R1LV0816ASD-7SI				(normal-bend type) (52PTG)		

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Pin Arrangement



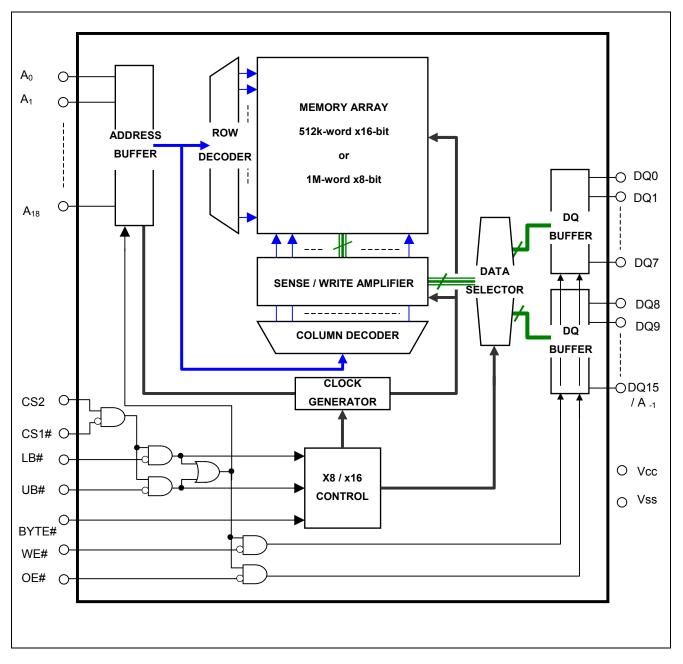
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Pin Description

Pin name	Function
Vcc	Power supply
Vss	Ground
A0 to A18	Address input (word mode)
A-1 to A18	Address input (byte mode)
DQ0 to DQ15	Data input/output
CS1#	Chip select 1
CS2	Chip select 2
WE#	Write enable
OE#	Output enable
LB#	Lower byte enable
UB#	Upper byte enable
BYTE#	Byte control mode enable
NC	Non connection



Block Diagram



Operation Table

CS1#	CS2	BYTE#	LB#	UB#	WE#	OE#	DQ0~7	DQ8~14	DQ15	Operation
Н	Х	Х	Х	Х	Х	Х	High-Z	High-Z	High-Z	Stand-by
Х	L	Х	Х	Х	Х	Х	High-Z	High-Z	High-Z	Stand-by
Х	Х	Н	Н	H	Х	Х	High-Z	High-Z	High-Z	Stand-by
L	Н	Н	L	Н	L	Х	Din	High-Z	High-Z	Write in lower byte
L	Н	Н	L	Н	H	L	Dout	High-Z	High-Z	Read in lower byte
L	Н	Н	L	H	H	Н	High-Z	High-Z	High-Z	Output disable
L	Н	Н	Н	L	L	Х	High-Z	Din	Din	Write in upper byte
L	Н	Н	Н	L	Н	L	High-Z	Dout	Dout	Read in upper byte
L	Н	Н	Н	L	H	Н	High-Z	High-Z	High-Z	Output disable
L	Н	Н	L	L	L	Х	Din	Din	Din	Word write
L	Н	Н	L	L	H	L	Dout	Dout	Dout	Word read
L	Н	Н	L	L	H	Н	High-Z	High-Z	High-Z	Output disable
L	Н	L	L	L	L	Х	Din	High-Z	A-1	Byte write
L	Н	L	L	L	H	L	Dout	High-Z	A-1	Byte read
L	Н	L	L	L	Н	Н	High-Z	High-Z	A-1	Output disable

Note 1. H: V_{IH} L: V_{IL} X: V_{IH} or V_{IL}

2. When BYTE#="L", both LB# and UB# must be active. (LB#=UB#="L")

Absolute Maximum Ratings

Parameter	Symbol	Value	unit
Power supply voltage relative to Vss	Vcc	-0.5 to +4.6	V
Terminal voltage on any pin relative to Vss	VT	-0.5 ^{*1} to Vcc+0.3 ^{*2}	V
Power dissipation	PT	0.7	W
Operation temperature	Topr	-40 to +85	°C
Storage temperature range	Tstg	-65 to 150	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

2. Maximum voltage is +4.6V



Recommend Operating Conditions

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Supply voltage	Vcc	2.4	3.0	3.6	V	-	
	Vss	0	0	0	V	-	
Input high voltage	V	2.0	-	Vcc+0.2	V	Vcc=2.4V to 2.7V	
	V _{IH}	2.2	-	Vcc+0.2	V	Vcc=2.7V to 3.6V	
Input low voltage	V	-0.2	-	0.4	V	Vcc=2.4V to 2.7V	1
	VIL	-0.2	-	0.6	V	Vcc=2.7V to 3.6V	1
Ambient temperature range	Та	-40	-	+85	°C	-	

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

DC Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit		Test conditions	
Input leakage current	I _{LI}	-	-	1	μA	Vin = Vss	to Vcc	
Output leakage current	I _{LO}	-	-	1	μA	CS1# =V _I OE# =V _{IH}	Vcc -0.2V or BYTE# \leq 0.2V _H or CS2 =V _{IL} or or WE# =V _{IL} or # =V _{IH} , VI/O =Vss to Vcc	
Average operating current	Icc1	-	20 ^{*1}	35	mA	Min. cycle, duty =100%, II/O = 0mA BYTE# \geq Vcc -0.2V or BYTE# \leq 0.2 CS1# =V _{IL} , CS2 =V _{IH} , Others = V _{IH} /		
	I _{CC2}	-	2 ^{*1}	5	mA	BYTE# ≥ CS1# ≤ 0	as, duty =100%, II/O = 0mA Vcc -0.2V or BYTE# ≤ 0.2V .2V, CS2 ≥ V_{CC} -0.2V, -0.2V, V _{IL} ≤ 0.2V	
Standby current	I _{SB}	-	0.1 ^{*1}	0.3	mA	BYTE#≥ CS2 =V _{IL}	Vcc -0.2V or BYTE# ≤ 0.2V	
Standby current		-	1.2 ^{*1}	4	μA	~+25°C	Vin ≥ 0V BYTE# ≥ Vcc -0.2V or	
		-	3 ^{*2}	6	μA	~+40°C	BYTE# $\leq 0.2V$ (1) 0V $\leq CS2 \leq 0.2V$ or (2) CS4# $\geq V = 0.2V$	
	I _{SB1}	-	-	15	μA	~+70°C	(2) $CS1\# \ge V_{CC}-0.2V$, $CS2 \ge V_{CC}-0.2V$ or (3) $LB\# = UB\# \ge V_{CC}-0.2V$,	
		-	-	20	μA	~+85°C	$CS1\# \le 0.2V,$ $CS2 \ge V_{CC}-0.2V$	
Output high voltage	V _{OH}	2.4	-	-	V	$BYTE# \ge Vcc -0.2V \text{ or } BYTE# \le 0.2V$ $I_{OH} = -1mA$ $Vcc \ge 2.7V$ $BYTE# \ge Vcc -0.2V \text{ or } BYTE# \le 0.2V$ $I_{OH} = -0.1mA$ $BYTE# \ge Vcc -0.2V \text{ or } BYTE# \le 0.2V$ $I_{OL} = 2mA$ $Vcc \ge 2.7V$ $BYTE# \ge Vcc -0.2V \text{ or } BYTE# \le 0.2V$ $I_{OL} = 0.1mA$		
	V _{OH2}	2.0	-	-	V			
Output low voltage	V _{OL}	-	-	0.4	v			
	V _{OL2}	-	-	0.4	V			

Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested. 2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested.



Capacitance

(Ta =25°C, f =1MHz)

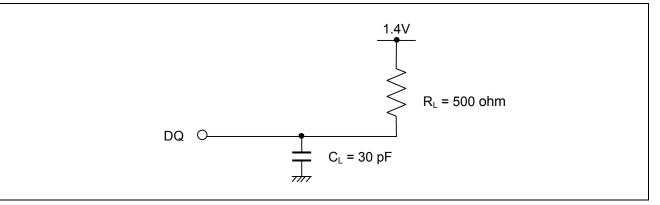
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	-	-	10	pF	Vin =0V	1
Input / output capacitance	C I/O	-	-	10	pF	V _{I/O} =0V	1

Note 1.Typical parameter is sampled and not 100% tested.

AC Characteristics

Test Conditions (Vcc = $2.4V \sim 3.6V$, Ta = $-40 \sim +85^{\circ}C$)

- Input pulse levels: VIL = 0.4V, VIH = 2.4V (Vcc = 2.7V ~ 3.6 V)
 VIL = 0.4V, VIH = 2.2V (Vcc = 2.4V ~ 2.7 V)
- Input rise and fall times: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



Read cycle

Parameter	Symbol	R1LV0816 (Not	ASD-5SI te 0)	R1LV081	6ASD-7SI	Unit	Note
		Min.	Max.	Min.	Max.		
Read cycle time	t _{RC}	55	-	70	-	ns	
Address access time	t _{AA}	-	55	-	70	ns	
Chip select access time	t _{ACS1}	-	55	-	70	ns	
	t _{ACS2}	-	55	-	70	ns	
Output enable to output valid	t _{OE}	-	30	-	35	ns	
Output hold from address change	t _{он}	10	-	10	-	ns	
LB#, UB# access time	t _{BA}	-	55	-	70	ns	
Chip select to output in low-Z	t _{CLZ1}	10	-	10	-	ns	2,3
	t _{CLZ2}	10	-	10	-	ns	2,3
LB#, UB# enable to low-Z	t _{BLZ}	5	-	5	-	ns	2,3
Output enable to output in low-Z	t _{OLZ}	5	-	5	-	ns	2,3
Chip deselect to output in high-Z	t _{CHZ1}	0	20	0	25	ns	1,2,3
	t _{CHZ2}	0	20	0	25	ns	1,2,3
LB#, UB# disable to high-Z	t _{BHZ}	0	20	0	25	ns	1,2,3
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1,2,3



Write Cycle

Parameter	Symbol	R1LV0816 (Not	ASD-5SI te 0)	R1LV081	6ASD-7SI	Unit	Note
		Min.	Max.	Min.	Max.		
Write cycle time	t _{wc}	55	-	70	-	ns	
Address valid to end of write	t _{AW}	50	-	65	-	ns	
Chip select to end of write	t _{CW}	50	-	65	-	ns	5
Write pulse width	t _{WP}	40	-	55	-	ns	4
LB#, UB# valid to end of write	t _{BW}	50	-	65	-	ns	
Address setup time	t _{AS}	0	-	0	-	ns	6
Write recovery time	t _{WR}	0	-	0	-	ns	7
Data to write time overlap	t _{DW}	25	-	35	-	ns	
Data hold from write time	t _{DH}	0	-	0	-	ns	
Output enable from end of write	t _{ow}	5	-	5	-	ns	2
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1,2
Write to output in high-Z	t _{WHZ}	0	20	0	25	ns	1,2

Note 0. If Vcc is 2.4-2.7V, parameters of R1LV0816ASA-7SI and R1LV0816ASD-7SI7SI are applied.

- 1. t_{CHZ} , t_{OHZ} , t_{WHZ} and t_{BHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
- 2. Typical parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition, t_{HZ} max is less than t_{LZ} min both for given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or low UB#. A write begins at the latest transitions among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low.

A write ends at the earliest transitions among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. t_{WP} is measured from the beginning of write to the end of write.

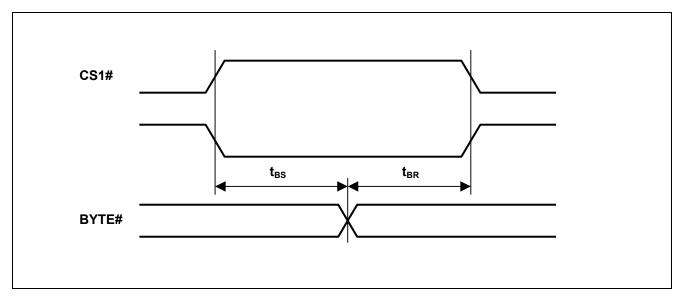
- 5. t_{CW} is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6. $t_{\mbox{\scriptsize AS}}$ is measured the address valid to the beginning of write.

7. twR is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle

BYTE# function

Parameter	Svmbol	R1LV081	6ASD-5SI	R1LV081	6ASD-7SI	Unit	Note
Falameter	Symbol	Min.	Max.	Min.	Max.	Unit	NOLE
Byte setup time	t _{BS}	5	-	5	-	ms	
Byte recovery time	t _{BR}	5	-	5	-	ms	

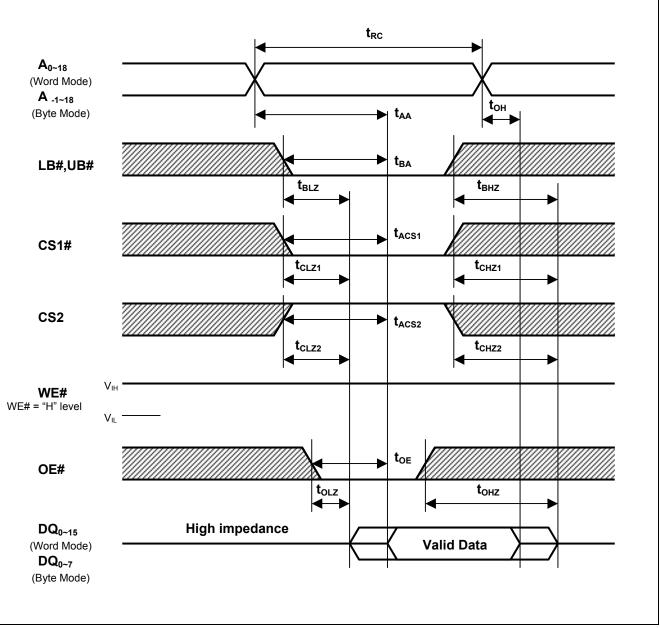
BYTE# Timing Waveforms





Timing Waveforms

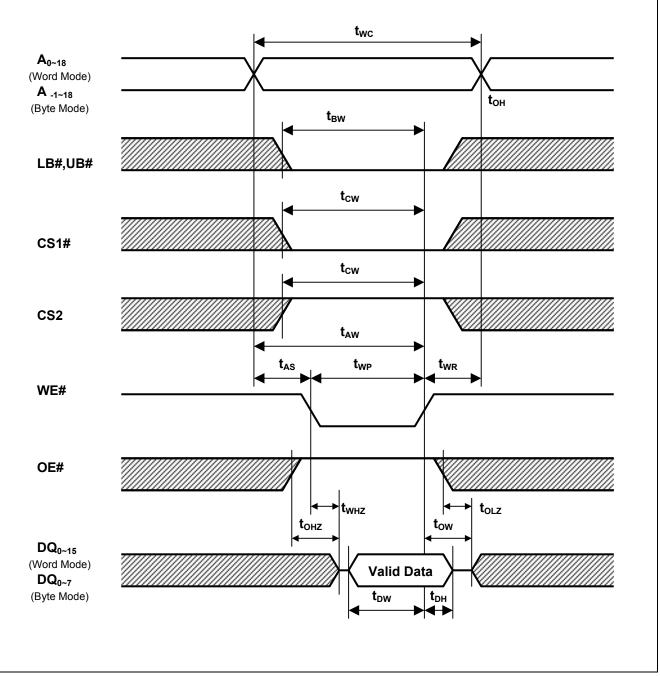
Read Cycle^{*1}



Note1.BYTE# \geq Vcc - 0.2V or BYTE# \leq 0.2V

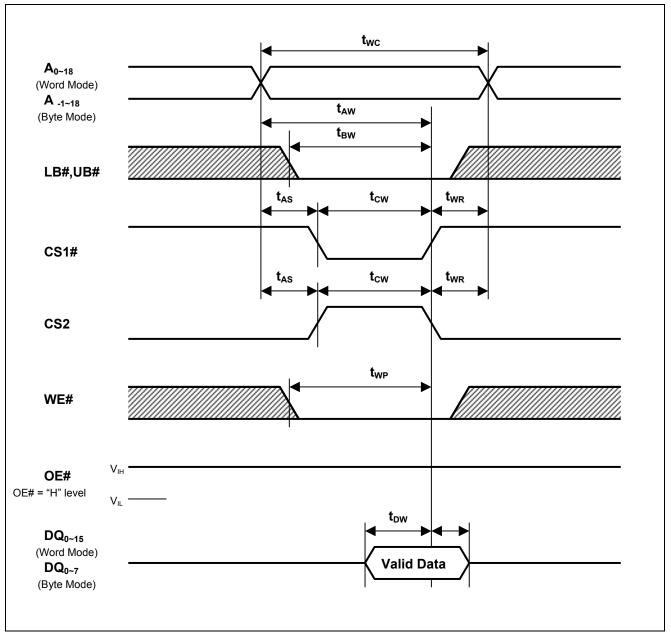
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Write Cycle (1)^{*1} (WE# CLOCK)



Note1.BYTE# \geq Vcc - 0.2V or BYTE# \leq 0.2V

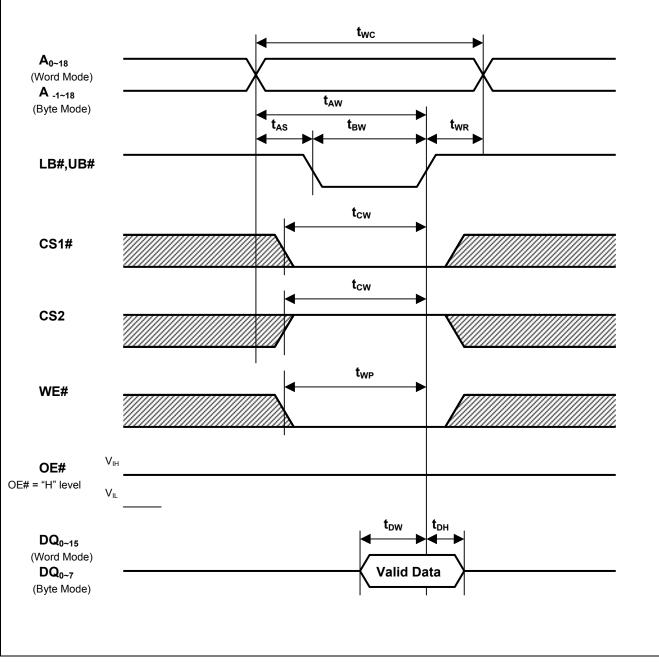
Write Cycle (2)^{*1} (CS1#, CS2 CLOCK)



Note1.BYTE# \geq Vcc - 0.2V or BYTE# \leq 0.2V

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Write Cycle (3)^{*1} (LB#, UB# CLOCK)



Note1.BYTE# \geq Vcc - 0.2V or BYTE# \leq 0.2V

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Data Retention Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit		Test conditions ^{*3}	
V_{CC} for data retention	V _{DR}	1.5	-	3.6	~	(1) 0V ≤ 0 (2) CS1# CS2 ≥ (3) LB# = CS1# ≤	Vcc -0.2V or BYTE# ≤ 0.2V CS2 ≤ 0.2V or ≥ V _{CC} -0.2V, V _{CC} -0.2V or : UB# ≥ V _{CC} -0.2V, ≤ 0.2V, V _{CC} -0.2V	
		-	1.2 ^{*1}	4	μA	~+25°C	Vcc=3.0V, Vin ≥ 0V BYTE# ≥ Vcc -0.2V or	
Data retention current		-	3 ^{*2}	6	μA	~+40°C	BYTE# $\leq 0.2V$ (1) 0V $\leq CS2 \leq 0.2V$ or (2) CS4# $\geq V$ = 0.2V	
	I _{CCDR}	-	-	15	μA	~+70°C	(2) CS1# \geq V _{CC} -0.2V, CS2 \geq V _{CC} -0.2V or (3) LB# = UB# \geq V _{CC} -0.2V,	
		-	-	20	μA	~+85°C	$CS1\# \le 0.2V,$ $CS2 \ge V_{CC}-0.2V$	
Chip select to data retention time	t _{CDR}	0	-	-	ns	See reter	ation waveform	
Operation recovery time	t _R	5	-	-	ms	See retention waveform.		

Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested.

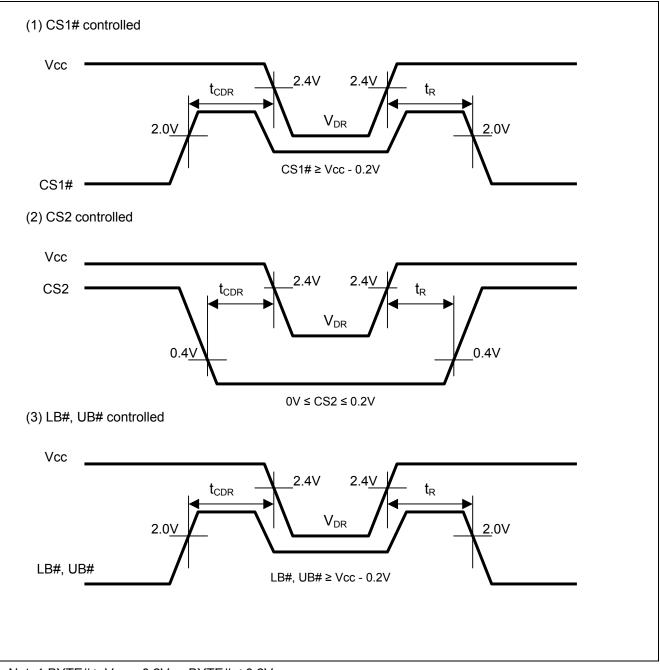
2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested.
3.CS2 controls address buffer, WE# buffer, CS1# Buffer, OE# buffer, LB#, UB# buffer and Din buffer.

If CS2 controls data retention mode, Vin levels (address, WE#, OE#, LB#, UB#, DQ) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2 \ge V_{CC}-0.2V or 0V \le CS2 \le 0.2V. The other inputs levels (address, WE#, OE#, CS1#, LB#, UB#, DQ) can be in the high impedance state.

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Data Retention Timing Waveforms^{*1}



Note1.BYTE# \geq Vcc - 0.2V or BYTE# \leq 0.2V

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